

# 64-Word x 9-Bit FIFO Register; 3-State

## **Type Features:**

- Synchronous or asynchronous operation
- 3-state outputs (standard)
- Master-reset inputs to clear data and control functions
- 25-MHz (typ.) shift-in, shift-out rates with flags
- 40-MHz (typ.) burst-in, burst-out rates without flags
- Cascadable to 25 MHz (typ.)
- Readily expandable in word and bit dimensions
- Pinning arranged for easy board layout: input pins directly opposite output pins
- Icc category: LSI
- Functionally equivalent and pin capatible with the TRW to TDC1030

The RCA-CD54HC/HCT7030 and CD74HC/HCT7030 are high-speed expandable silicon-gate CMOS first-in first-out (FIFO) memories organized as 64-word by 9-bit registers. A 25-MHz data-rates makes them ideal for high-speed applications. Burst data-rates of 40 MHz can be obtained in applications where the status flags are not used.

With separate controls for Shift-In (SI) and Shift-Out ( $\overline{SO}$ ), reading and writing operations are completely independent, allowing synchronous and asynchronous data transfers. Additional controls include a Master-Reset input ( $\overline{MR}$ ) and and Output Enable Input ( $\overline{OE}$ ). Flags for Data-In-Ready (DIR) and Data-Out-Ready (DOR) indicate the status of the device.

Devices can be interconnected easily to expand word and bit dimensions. All output pins are directly opposite the corresponding input pins thus simplifying board layout in expanded applications.

#### INPUTS AND OUTPUTS

### Data Inputs (Do to Da)

As there is no weighting of the inputs, any input can be assigned as the MSB. The size of the FIFO memory can be reduced from the 9 x 64 configuration, i.e. 8 x 64, 7 x 64, down to 1 x 64, by tying unused data input pins to  $V_{\rm CC}$  or GND.

# Data Outputs (Qo to Qs)

As there is no weighting of the outputs any output can be assigned as the MSB. The size of the FIFO memory can be reduced from the 9 x 64 configuration as described for data inputs. In a reduced format, the unused data output pins must be left open.

## Master-Reset (MR)

When  $\overline{\text{MR}}$  is LOW, the control functions within the FIFO are cleared and data content is declared invalid; the Data-In-Ready (DIR) flag is set HIGH and the Data-Out-Ready flag (DOR) is set LOW. The output stage remains in the state of the last word that was shifted out, or in the random state existing at power-up.

### Applications:

- Bit-rate smoothing
- CPU/terminal buffering
- Data communications
- Peripheral buffering
- Line printer input buffers
- Auto-dialers
- CRT buffer memories
- Radar data acquisition
- High-speed disc or tape controller
- Video synthesis
- I/O formatter for digital filters and FFTs

#### Family Features:

- Fanout (Over Temperature Range): Standard Outputs - 10 LSTTL Loads Bus Driver Outputs - 15 LSTTL Loads
- Wide Operating Temperature Range: CD74HC/HCT: -40 to +125° C
- Balanced Propagation Delay and Transition Times
- Significant Power Reduction Compared to LSTTL Logic ICs
- Alternate Source is Philips/Signetics
- CD54HC/CD74HC Types: 2 to 6 V Operation High Noise Immunity: N<sub>IL</sub> = 30%, N<sub>IH</sub> = 30% of V<sub>CC</sub>, @ V<sub>CC</sub> = 5 V
- CD54HCT/CD74HCT Types 4.5 to 5.5 V Operation Direct LSTTL Input Logic Compatibility V<sub>IL</sub> = 0.8 V Max., V<sub>IH</sub> = 2 V Min. CMOS Input Compatibility I<sub>1</sub> ≤ 1 μA @ V<sub>OL</sub>, V<sub>OH</sub>

### Status Flag Outputs (DIR, DOR)

Indication of the status of the FIFO is given by two status flags, Data-In-Ready (DIR) and Data-Out-Ready (DOR):

DIR = HIGH indicates the input stage is empty and ready to accept valid data;

DIR = LOW indicates that the FIFO is full or that a previous shift-in operation is not complete;

DOR = HIGH assures valid data is present at the outputs  $Q_0$  to  $Q_0$  (does not indicate that new data is awaiting transfer into the output stage);

DOR = LOW indicates the output stage is busy or there is no valid data.

#### Shift-In Control (SI)

Data is loaded into the input stage on a LOW-to-HIGH

transition of SI. A HIGH-to-LOW transition triggers an automatic data transfer process (ripple-through).

### Shift-Out Control (SO)

A LOW-to-HIGH transition of  $\overline{SO}$  causes the DOR flag to go LOW. A HIGH-to-LOW transition of  $\overline{SO}$  causes upstream data to move into the output stage, and empty locations to move towards the input stage (bubble-up).

# Output Enable (OE)

The outputs  $Q_0$  to  $Q_0$  are enabled when  $\overrightarrow{OE} = LOW$ . When  $\overrightarrow{OE} = HIGH$  the outputs are in the high impedance OFF-State.

These types are supplied in 28-lead dual-in-line plastic package E suffix. These types are also available in pellet (die) form H suffix.

#### MAXIMUM RATINGS, Absolute-Maximum Values:

DC SUPPLY-VOLTAGE, (Vcc):	
(Voltage referenced to ground)	٧
DC INPUT DIODE CURRENT, $I_{IK}$ (FOR $V_I < -0.5$ V OR $V_I > V_{CC} +0.5$ V)	A
DC OUTPUT DIODE CURRENT, I <sub>OK</sub> (FOR V <sub>0</sub> < -0.5 V OR V <sub>0</sub> > V <sub>CC</sub> +0.5 V)	A
DC DRAIN CURRENT, PER OUTPUT (I <sub>0</sub> ) (FOR -0.5 V < V <sub>0</sub> < V <sub>0c</sub> +0.5 V):	
STANDARD OUTPUT±25 m/	A
BUS DRIVER OUTPUT±35 m/	Α
DC V <sub>CC</sub> OR GROUND CURRENT, (I <sub>CC</sub> ):	
STANDARD OUTPUT	Α
BUS DRIVER OUTPUT±70 m/	Α
POWER DISSIPATION PER PACKAGE (Po):	
For T <sub>A</sub> = -40 to +100°C (PACKAGE TYPE E)	٧
For T <sub>A</sub> = +100 to +125°C (PACKAGE TYPE E)	٧
For T <sub>A</sub> = -55 to +100°C (PACKAGE TYPE H)	٧
For T <sub>A</sub> = +100 to +125°C (PACKAGE TYPE H)	٧
OPERATING-TEMPERATURE RANGE (T <sub>A</sub> ):	
PACKAGE TYPE F, H	С
PACKAGE TYPE E, M40 to +125°(	С
STORAGE TEMPERATURE (Tata) -65 to +150°C	C
LEAD TEMPERATURE (DURING SOLDERING):	
At distance $1/16 \pm 1/32$ in. $(1.59 \pm 0.79$ mm) from case for $10$ s max	С
Unit inserted into a PC Board (min. thickness 1/16 in., 1.59 mm)	
with solder contacting lead tips only	С

## **RECOMMENDED OPERATING CONDITIONS**

For maximum reliability, nominal operating conditions should be selected so that operation is always within the following ranges:

	LIN				
CHARACTERISTIC	MIN.	MAX.	UNITS		
Supply-Voltage Range (For T <sub>A</sub> = Full Package Temperature Range) V <sub>cc</sub> : *					
CD54/74HC Types	2	6			
CD54/74HCT Types	4.5	5.5	V		
DC Input or Output Voltage, V <sub>I</sub> , V <sub>O</sub>	0	Vcc			
Operating Temperature, T <sub>A</sub> :					
CD74 Types	-40	+125	l ∘c		
CD54 Types	-55	+125			
Input Rise and Fall Times, tr. tr:					
at 2 V	0	1000			
at 4.5 V	0	500	ns		
at 6 V	0	400			

\* Unless otherwise specified, all voltages are referenced to Ground.

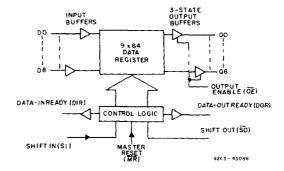


Fig. 1 - Functional block diagram.

GND	1	28	v <sub>cc</sub>
GND	2	27	MR
DIR.	3	26	<u>S</u> ō
SI	4	25	DOR
00	5	24	00
סו	6	23	01
02	7	22	Q2
D3	8	21	Q3
04	9	20	04
D5	10	19	Q5
D6	11	18	06
07-	12	17	07
DB	13	16	08
GND.	14	15	ÕĒ
1		9205	42858

Fig. 2 - Terminal connections.

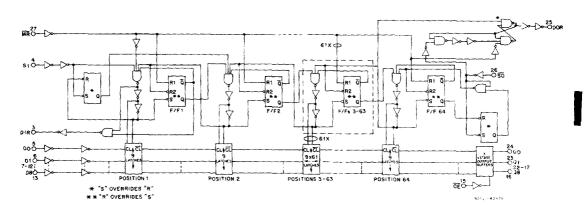


Fig. 3 - Logic diagram.

# STATIC ELECTRICAL CHARACTERISTICS

			C	CD74I	HC70:	30/CI	)54H(	C7030	)			CD74HCT7030/CD54HCT7030														
014.0.	<b>-</b> 10	1	TEST	15	ł	C/54 YPE		741 TYF		541 TYF		TEST CONDITIONS		74HCT/54HCT												
CHARACTERIS	TIC	V.	l <sub>o</sub>	Vcc	,	25°C	:	-4: +85		-5 +12		٧,	Vcc		+25° C	;	I	0/ 5°C	I	5/ 5°C	UNITS					
		٧	mA	v	Min	Тур	Max	Min	Max	Min	Max	٧	V	Min	Тур	Max	Min	Max	Min	Max						
High-Level				2	1.5	_	-	1.5		1.5			4.5					T	<u> </u>							
Input Voltage	ViH			4.5	3.15	_	1=	3.15	-	3.15			to	2		_	2	-	2	l _						
				6	4.2		_	4.2	_	4.2			5.5													
Low-Level				2	_		0.5	_	0.5	_	0.5		4.5								1					
Input Voltage	VIL		i	4.5	_		1.35		1.35		1.35	_	to	_	_	0.8	_	0.8	_	0.8	1					
		İ		6			1.8	_	1.8		1.8		5.5						l		ľ					
High-Level		VIL		2	1.9	_	_	1.9	-	1.9		V <sub>iL</sub>									•					
Output Voltage	Von	ar	-0.02	4.5	4.4			4.4		4.4	~~	or	4.5	4.4		_	4.4	-	4.4	l						
CMOS Loads		V <sub>tH</sub>		6	5.9	-		5.9	_	5.9		VIH	İ								] <sub>v</sub>					
		Vil					1					٧٠١									1 "					
TTL Loads		or	-4	4.5	3.98	_	<u> </u>	3.84	-	3.7	_	or	4.5	3.98	l –	l –	3.84		3.7	-						
		VIH	-5.2	6	5.48	_	_	5.34	_	5.2	_	ViH		ľ				•		ł	ļ					
Low-Level		VIL		2	_	-	0.1	_	0.1	_	0.1	VIL			1			-			1					
Output Voltage	VoL	or	0.02	4.5		_	0.1	_	0.1	_	0.1	or	4.5	l –	-	0.1	_	0.1	_	0.1	ļ					
CMOS Loads		ViH		6	Ι-	_	0.1	_	0.1	_	0.1	V <sub>IH</sub>			i			ĺ								
		V <sub>IL</sub>										Vil									1					
TTL Loads		or	4	4.5	_	_	0.26		0.33		0.4	or	4.5	_	-	0.26		0.33	_	0.4						
		VIH	5.2	6	_	_	0.26		0.33	_	0.4	ViH	l	1	1	İ		Ì			Ì					
Input Leakage							T					Any														
Current	l <sub>1</sub>	Vcc					١.,	ļ				Voltage	l					١		١						
		or		6		_	±0.1	-	±1	_	±1	Between	5.5	-	-	±0.1	_	±1	-	±1	İ					
		Gnd			Ì							Vcc & Gnd	ĺ													
Quiescent		Vcc										Vcc							l							
Device Current	lcc	or	0	6	-	-	50	-	500		1000	or	5.5	-		50	-	500	-	1000						
(LSI)		Gnd										Gnd									μA					
Additional													4.5								, ,					
Quiescent Device												Vcc -2.1	14.5 to	_	100	360	_	450	_	490						
Current per input												VCC -2.1	5.5	-	100	360	_	450	_	490						
pin: 1 unit load	Δl <sub>cc</sub> *												5.5													
3-State Leakage		VIL	Vo=Vo									VIL														
Current	loz	or	or	6	-	-	±0.5	-	±5		±10	or	5.5	-	-	±0.5		±5	-	±10						
		VIH	Gnd			İ						V <sub>tH</sub>				1	-			1						

<sup>\*</sup>For dual-supply systems theoretical worst case (V<sub>i</sub> = 2.4 V,  $V_{CC}$  = 5.5 V) specification is 1.8 mA.

# **HCT INPUT LOADING TABLE**

INPUT	UNIT LOADS *
ŌĒ	1
SI, SO, MR	1.5
Dn	0.75

<sup>\*</sup> Unit Load is ΔI<sub>CC</sub> limit specified in Static Characteristics Chart, e.g., 360 μA max. @ 25° C.

# SWITCHING CHARACTERISTICS ( $V_{CC} = 5 \text{ V}$ , $T_A = 25^{\circ}\text{ C}$ , input $t_r$ , $t_t = 6 \text{ ns}$ )

CHARACTERISTIC		C,	TYP	T		
Characteristic		(pF)	HC	HCT	UNITS	
Propagation Delay	tplH				1	
	t <sub>PHL</sub>	<u> </u>				
MR to DIR, DOR		ļ	21	26	ns	
SO to Q <sub>n</sub>	<del></del>	15	36	40	7	
SI to DIR	tpHL	Ī	20	21	1	
SO to DOR		ŀ	25	26	7	
Maximum SI, SO Frequency		15	33	29	MHz	
Power Dissipation Capacitance *	CPD	-	660	660	pF	

<sup>\*</sup> CPo is used to determine the dynamic power consumption, per package.

 $P_D = C_{PD} V_{CC}^2 f_i + \Sigma (C_L V_{CC}^2 f_o)$  where:  $f_i = \text{input frequency}$ 

f<sub>i</sub> = input frequency f<sub>o</sub> = output frequency C<sub>L</sub> = output load capacitance

V<sub>cc</sub> = supply voltage

# PRE-REQUISITE FOR SWITCHING FUNCTION

		TEST						LIM	ITS						
CHARACTERISTIC		CONDITIONS		+25			-4	0° C t	o +85°	С	-55	5° C to	+125	, C	UNITS
		V <sub>cc</sub> (V)	Н	C		CT		HC	74h	ICT	54	HC		CT	UNITS
		*CC (*)	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	 <del> </del>
SI Pulse Width	tw	2	50	-	-	-	65	:		-	75	-	-	-	
HIGH or LOW		4.5	10	-	12		13	-	15	-	15	-	18		
Fig. 4		6	9		_		11				13				
SO Pulse Width	tw	2	100	-	-		125			-	150		-	-	
HIGH or LOW		4.5	20	- :	15		25		19	-	30		22		ľ
Fig. 7		6	_17		_	~	21		-	_	26				
DIR Pulse Width	tw	2	50	145	-	_	-	180	-	_	_	220			
HIGH		4.5	10	29	13	37	_	36	_	46		44	-	56	
Fig. 5		6	9	25	_	-	_	31			_	38	-		
DOR Pulse Width	tw	2	50	145	-			180		-		220	-	-	
HIGH		4.5	10	29	12	35	_	36		44		44	-	53	
Fig. 8		6	9	29			_	31	_	_	_	38	_		
MR Pulse Width	tw	2	70	-	_	_	90			_	105		_	-	ns
LOW		4.5	14	_	18		18		23	-	21	_	27	-	
Fig. 6		6	12	_	_		15		-	_	18	-	_		
Removal Time	1 <sub>REM</sub>	2	80	-	_	-	100	_	-	1	120	-	_		
MR to SI		4.5	16	_	18	-	20		23	_	24	_	27		
Fig. 13		6	14	-	_		17		-	_	20	_	-		
Setup Time	tsu	2	-35	-	-	-	-45	_	-		-55	-	_	_	
D <sub>n</sub> to SI		4.5	-7	-	-8		-9		-10	- 1	-11	-	-12	-	
Fig. 11		6	-6	_	-		-8	-		-	-9		_	-	
Hold Time		2	110	_			140				165	-	_		
D <sub>n</sub> to SI		4.5	22	-	22		28		28	- :	33	-	33		
Fig. 11		6	19	_	_	-	24				28	_	_	_	
Maximum Clock Pulse Pulse Frequency	f <sub>MAX</sub>	2	3.6	_	_	-	2.8	_		_	2.4	-	_		
SI, SO (Burst Mode or Using Flags)		4.5	18	_	15	-	14	-	12	-	12	-	10		
Figs. 4, 7, 9 and 10		6	21			<u> </u>	16				14	<u> </u>			MHz
Maximum Clock Pulse Frequency	f <sub>MAX</sub>	2	2.8	-	-		2.2	-	-		1.8	-			
St, SO (Cascaded)		4.5	14	-	13	-	11	-	10	-	9.2	-	7.8		
Figs. 4 and 7		6	17	L =			13			<u> </u>	11	<u> </u>		<u></u>	L

# SWITCHING CHARACTERISTICS (CL = 50 pF, Input t, t, = 6 ns)

		LIMITS													
CHARACTERISTIC		TEST		+25	°C		-4	10°C 10	+85°	С	-5	5°C to	+125°	,c	UNITS
CHARACTERISTIC		V <sub>cc</sub> (V)	н	С	нст		74HC		74HCT		54HC		54HCT		UNITS
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
Propagation Delay	tpHL	2		210	_	-	_	265			_	315	_	_	
MR to DIR, DOR	tpLH	4.5	-	42	-	51	_	53	-	53		63	-	63	
Fig. 6		6	_	36	_	<u> </u>	_	45		_		54	_	_	
Propagation Delay	tplH	2	_	235	-	_	-	295	_		_	355	_	_	
SI to DIR		4.5		47	_	49		59		61		71	-	74	
Fig. 4		6	_	40	_	<u> </u>	_	50		_		60	_		
Propagation Delay	t <sub>PHI</sub> .	2	_	315	T =	_		395	-	-	_	475		_	
SO to DOR		4.5		63		67	_	79		84	_	95	_	101	ns
Fig. 7		6		50	_	_	L	63		_	_	76	_	-	
Propagation Delay	t <sub>PHL</sub>	2		35	_	Γ-	-	45	-	-	_	55	_	-	
DOR to Q <sub>n</sub>	tpLH	4.5	_	7		22		9		28	-	11	-	33	
Fig. 8		6	_	6	_			8		_	<u></u>	9		L	
Propagation Delay	t <sub>PHL</sub>	2		345	-	_	_	430		_	-	520	_	_	
SO to Qn	t <sub>PLH</sub>	4.5	_	69	_	78	_	86		98	_	104	-	117	
Fig. 12		6	_	55	_	_	_	69	_	_		83	_	-	
Propagation Delay	t <sub>PLI4</sub>	2	-	8	-	_	_	10	-		"	12	_	_	
Ripple through Delay		4.5		1.6	-	1.6	-	2	-	2		2.4	_	2.4	
Si to DOR Fig. 8		6		1.3				1.6		L	_	1.9	_		_
Propagation Delay	t <sub>PLH</sub>	2		10	_		_	12.5		-	-	15	_	_	μs
Ripple through Delay		4.5	_	2	—	2	_	2.5	-	2.5	-	3	-	3	
SO to DIR Fig. 5		6		1.6	_	_	_`	2	_		<u> </u>	2.4			
3-State Output Enable	tpzH	2		175		-	_	220	_	_	-	265	-	_	]
OE to Q <sub>n</sub>	tezL	4.5	_	35	_	35		44		44	-	53	-	53	
Fig. 14		6		30	_	-	_	37	L		L_	45	<u> </u>		]
3-State Output Disable	t <sub>PHZ</sub>	2	-	150	Γ-	-	-	190	-	-	-	225	_	_	
OE to Q <sub>n</sub>	† <sub>PLZ</sub>	4.5		30	-	35	-	38	~	44	-	45	-	53	ns
Fig. 14		6		26	<u> </u>	<u> </u>		33		_	] —	38	_		]
Output Transition Time	tthe	2		75	<b>]</b> —	-	-	95	-	-	-	110	-	-	]
Standard Outputs	*TLH	4.5	-	15	-	15	-	19	-	19	-	22	_	22	]
Fig. 12		6		13	_		_	16		<u>  = </u>	<u> </u>	19	_		
Input Capacitance	C <sub>1</sub>	_	_	10	_	10	_	10		10	_	10	_	10	·pF
3-State Output Capacita	ncejCo		_	15		15	<u> </u>	15		15	<u> </u>	15	<u> </u>	15	

#### **FUNCTIONAL DESCRIPTION**

#### **Data input**

Following power-up, the Master-Reset ( $\overline{MR}$ ) input is pulsed LOW to clear the FIFO memory. The Data-In-Ready flag (DIR = HIGH) indicates that the FIFO input stage is empty and ready to receive data. When DIR is valid (HIGH), data present at D<sub>0</sub> to D<sub>8</sub> can be shifted-in using the SI control input. With SI = HIGH, data is shifted into the input stage and a busy indication is given by DIR going LOW.

The data remains at the first location in the FIFO until SI is set to LOW. With SI = LOW the data moves through the FIFO to the output stage, or to the last empty location. If the FIFO is not full after the SI pulse, DIR again becomes valid (HIGH) to indicate that space is available in the FIFO. The DIR flag remains LOW if the FIFO is full (see Fig. 6).

With the FIFO full, SI can be held LOW until a Shift-Out ( $\overline{SO}$ ) pulse occurs. Then, following a Shift-Out of data, an empty location appears at the FIFO input and DIR goes HIGH to allow the next data to be Shifted-In (this data remains at the first FIFO location until SI again goes LOW) (see Fig. 5).

#### **Data Transfer**

After data has been transferred from the input stage to the FIFO following SI = LOW, the data moves through the FIFO asynchronous and is stacked at the output end of the register. Empty locations appear at the input end of the FIFO as the data moves through the device.

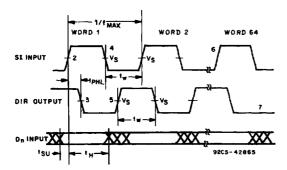
#### **Data Output**

The Data-Out Ready flag (DOR = HIGH) indicates that there is valid data the output ( $Q_0$  to  $Q_8$ ). The initial Master-Reset at power on ( $\overline{MR}$  = LOW) sets DOR to LOW (see Fig. 6).

After MR = HIGH, data shifted onto the FIFO moves through to the output stage causing DOR to go HIGH.

As the DOR flag goes HIGH, data can be shifted-out using the  $\overline{SO}$  control input. With  $\overline{SO}$  = HIGH, data in the output stage is shifted out and a busy indication is given by DOR going LOW. When  $\overline{SO}$  is made LOW, data moves through

## AC WAVEFORMS



The above waveforms show the SI input to DIR output propagation delay times; the SI, DIR pulse widths; and the SI maximum pulse-frequency.

Fig. 4 - Shift-In sequence timing waveforms (FIFO empty to FIFO full).

the FIFO to fill the output stage and an empty location appears at the input stage. When the output stage is filled DOR goes HIGH, but if the last of the valid data has been shifted out leaving the FIFO empty the DOR flag remains LOW (see Fig. 11). With the FIFO empty, the last word that was shifted-out is latched at the output Q<sub>0</sub> to Q<sub>8</sub>.

With the FIFO empty, the  $\overline{SO}$  input can be held HIGH until the SI control input is used. Following an SI pulse, data moves through the FIFO to the output stage, resulting in the DOR flag pulsing HIGH and a Shift-Out of data occuring. The  $\overline{SO}$  control must be made LOW before additional data can be shifted out (see Fig. 8).

#### **High-Speed Burst Mode**

If it is assumed that the Shift-In/Shift-Out pulses are not applied until the respective status flags are valid, it follows that the Shift-In/Shift-Out rates are determined by the status flags. However, without the status flags a high-speed burst-mode can be implemented. In this mode, the burst-in/burst-out rates are determined by the pulse-widths of the Shift-In/Shift-Out inputs and burst rates of 40 MHz can be obtained. Shift pulses can be applied without regard to the status flags but Shift-In pulses that would overflow the storage capacity of the FIFO are not allowed (see Fig. 9 and 10).

#### **Expanded Format**

With the addition of a logic gate, the FIFO is easily expanded to increase word length (see Fig. 19). The basic operation and timing are identical to a single FIFO, with the exception of an additional gate delay on the flag outputs. Word length can be expanded beyond the 18-bits x 64 words configuration shown in Fig. 15.

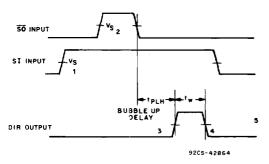
The "7030" is easily cascaded to increase the word capacity and no external components are needed. In the cascaded configuration, all necessary communications and timing are performed by the FIFOs themselves. The intercommunications speed is determined by the minimum flag pulse widths and the flag delays. The data rate of cascaded devices is typically 25 MHz. Word-capacity can be expanded to and beyond 128-words x 9-bits (see Fig. 16).

## **TEST VOLTAGES FOR FIGS. 4 TO 14.**

TEST VOLTAGE	54/74HC	54/74HCT
Input Level	Vcc	3 V
Switching Voltage, Vs	50% Vcc	1.3 V

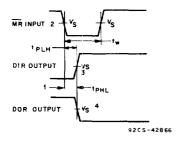
### NOTES:

- DIR initially HIGH; FIFO is prepared for valid data.
- 2. SI set HIGH; data loaded into input stage.
- 3. DIR drops LOW, input stage busy.
- 4. SI set LOW; data from first location "ripple through".
- DIR goes HIGH, status flag indicates FIFO prepared for additional data.
- Repeat process to load 2nd word through to 64th word into FIFO.
- DIR remains LOW; with attempt to shift into full FIFO, no data transfer occurs.



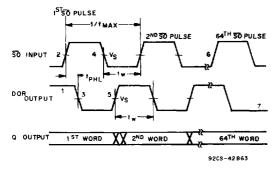
The above waveforms show bubble-up delay,  $\overline{SO}$  input to DIR output and DIR output pulse-width.

Fig. 5 - Bubble-up delay timing waveforms.



The above waveforms show  $\overline{MR}$  input to DIR, DOR output propagation delay times and the  $\overline{MR}$  pulse-width.

Fig. 6 - MR input timing waveforms.



The above waveforms show the  $\overline{SO}$  input to DOR output propagation delay times, the  $\overline{SO}$ , DOR pulse-widths, and  $\overline{SO}$  maximum pulse frequency.

Fig. 7 - SO input timing waveforms. (FIFO full to FIFO empty)

#### NOTES:

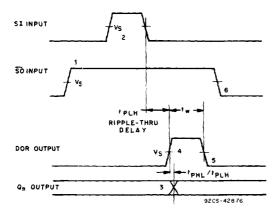
- 1. FIFO is initially full, shift-in is held HIGH.
- SO pulse; data in the output stage is unloaded, bubbleup process of empty location begins.
- DIR HIGH; when empty location reaches input stage, flag indicates FIFO is prepared for data input.
- DIR goes LOW; data shift-in to empty location is complete, FIFO is full again.
- SI brought LOW; necessary to complete shift-in process, DIR remains LOW, because FIFO is full.

#### NOTES:

- 1. DIR LOW, output ready HIGH; assume FIFO is full.
- 2. MR pulse LOW; clears FIFO.
- DIR goes HIGH; flag indicates input prepared for valid data.
- 4. DOR drops LOW; flag indicates FIFO empty.

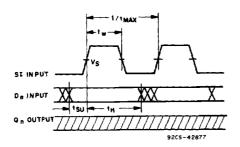
#### NOTES:

- DOR HIGH; no data transfer in progress, valid data is present at output stage.
- 2. SO set HIGH; results in DOR going LOW.
- 3. DOR drops LOW; output stage busy.
- SO set LOW; data in the input stage is unloaded, and new data replaces it as empty location bubbles-up to input stage.
- DOR goes HIGH; transfer process completed, valid data present at output.
- Repeat process to unload the 3rd through to the 64th word from FIFO after the specified propagation delay times.
- 7. DOR remains LOW; FIFO is empty.



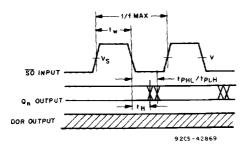
The above waveforms show ripple-through delay times, SI input to DOR output, DOR output pulse-width, and propagation delay times from the DOR pulse-width to the  $\mathbf{Q}_n$  output.

Fig. 8 - Ripple-through delay timing waveforms.



The above waveforms show SI minimum pulse-width and SI maximum pulse frequency, in high-speed Shift-In burst mode.

Fig. 9 - SI pulse-width timing waveforms.



The above waveforms show  $\overline{SO}$  minimum pulse-width and maximum pulse frequency, in high-speed, Shift-Out burst mode.

Fig. 10 - SO pulse-width timing waveforms.

### NOTES:

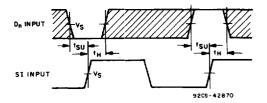
- 1. FIFO is initially empty, SO is held HIGH.
- SI pulse; loads data into FIFO and initiates ripple through process.
- Output transition; data arrrives at output stage (after specified propagation delay times between rising edge of the DOR pulse to Q<sub>n</sub> output).
- DOR HIGH; DOR flag signals the arrival of valid data at the output stage.
- DOR goes LOW; data shift-out is complete, FIFO is empty again.
- SO set LOW, necessary to complete shift-out process. DOR remains LOW, because FIFO is empty.

### NOTE:

In the high-speed mode, the burst-in rate is determined by the minimum Shift-In HIGH and Shift-In LOW specifications. The DIR status flag is a don't care condition, and a Shift-In pulse can be applied regardless of the flag. An SI pulse which would overflow the storage capacity of the FIFO is not permitted.

## NOTE:

In the high-speed mode, the burst-out rate is determined by the minimum Shift-Out HIGH and Shift-Out LOW specifications. The DOR flag is a don't care condition and an SO pulse can be applied regardless of the flag.

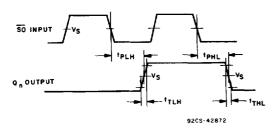


NOTE:

The shaded areas indicate when the input is permitted to change for predictable output performance.

The above waveforms show hold and set-up times for  $D_n$  and SI input.

Fig. 11 - Hold and set-up timing waveforms.



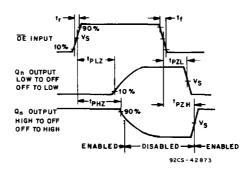
SI INPUT

The above waveforms show  $\overline{SO}$  input to  $Q_n$  output, propagation delay times, and output transistion times.

The above waveforms show  $\overline{\mbox{MR}}$  output and SI input removal time.

Fig. 12 - Propagation delay and transition timing waveforms.

Fig. 13 - Removal timing waveforms.



The above waveforms show the 3-state enable and disable times for input  $\overline{OE}$ .

Fig. 14 - 3-state enable and disable timing waveforms.

#### **Application Information on Expanded Format**

Fig. 16 shows two FIFOs connected in cascade. The obtained capacity is 128 words of 9 bits.

Fig. 17 shows the signals on the nodes of both FIFOs at the application of one Shift-In pulse when the FIFOs are initially empty. After a ripple through delay, data arrives at the output of FIFO A. As  $\overline{SO}(A)$  is HIGH at this time instant a DOR(A) pulse is generated. The width of this DOR(A) pulse and the timing between the rising edge of this pulse and the signal change of  $Q_n(A)$  meets the requirement of Si(B) and  $D_n(B)$  of FIFO B. After a second ripple through delay data arrives at the output of FIFO B ( $Q_n(B)$ ).

Fig. 18 shows the signals on these nodes after the application of an  $\overline{SO}(B)$  pulse when both FIFOs are initially full. After a bubble-up delay a DIR(B) pulse is generated that serves as a  $\overline{SO}(A)$  pulse for FIFO A. One word is transferred from the output of FIFO A to the input of FIFO B. The width of DIR(B) meets the requirements of the  $\overline{SO}(A)$  pulse of FIFO A. After a second bubble-up delay an empty space arrives at  $D_n(A)$  at which time instant DIR(A) goes HIGH.

Fig. 19 shows the waveforms at all external nodes of these two registers during a complete Shift-In and Shift-Out sequence.

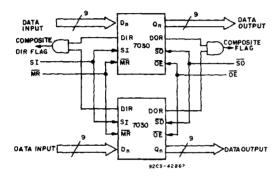


Fig. 15 - Functional diagram of expanded FIFO for increased word length - 64-words x 18-bits.

#### NOTE:

The 7030 is easily expanded to increase word length. Composite DIR and DOR flags are forced with the addition of an AND gate. The basic operation and timing are identical to a single FIFO, with the exception of an added gate delay for the flags.

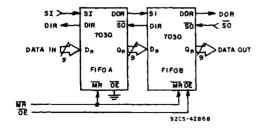


Fig. 16 - Functional diagram of cascaded FIFOs for increased word capacity - 128-words x 9-bits.

#### NOTE

The 7030 is easily cascaded to increase word capacity without any external circuitry. In cascaded format, all necessary communications are handled by the FIFOs. Fig. 19 demonstrates the intercommunication timing between FIFO A and FIFO B. Figs. 17 and 18 gives an overview of pulses and timing of two cascaded FIFOs, when shifted full and shifted empty again.

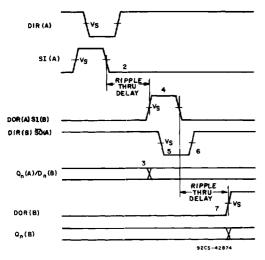


Fig. 17 - FIFO to FIFO communications timing waveforms, input timing under empty condition.

#### NOTES:

- FIFO(A) and (B) initially empty, SO(A) held HIGH in anticipation of data.
- Load one word into FIFO(A) SI pulse applied, results in DIR pulse.
- DOR(A) and SI(B) pulse HIGH; (ripple through delay after SI(A) LOW) data is unloaded from FIFO(A) as a result of the data output ready pulse, data is shifted into FIFO(B).
- Data-out(A)/data-in(B) transition; valid data arrives at FIFO(A) output stage simultaneously with DOR flag, meeting data input set-up requirements of FIFO(B).
- DIR(B) and SO(A) go LOW; flag indicates input stage of FIFO(B) is busy, shift-out of FIFO(A) is complete.
- DIR(B) and SO(B) go HIGH: automatically, input stage of FIFO(B) is again able to receive data, SO is held HIGH in anticipation of additional data.
- DOR(B) goes HIGH; (ripple through delay after SI(B) LOW) valid data is present one propagation delay-time later at the FIFO(B) output stage.

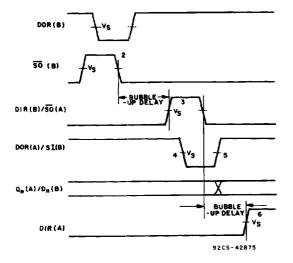


Fig. 18 - FIFO to FIFO communications timing waveforms, output timing under full condition.

#### NOTES:

- FIFO(A) and (B) initially full, SI(B) held HIGH in anticipation of shifting in new data as empty location bubbles-up.
- Unload one word from FIFO(B); SO pulse applied, results in DOR pulse.
- DIR B and SO(A) pulse HIGH; (bubble-up delay after SO(B) LOW) data is loaded into FIFO(B) as a result of the DIR pulse, data is shifted out of FIFO(A).
- DOR(A) and SI(B) go LOW; flag indicates the output stage of FIFO A is busy, shift-in to FIFO(B) is complete.
- DOR(A) and SI(B) go HIGH; flag Indicates valid data is again available at FIFO(A) output stage, SI(B) is held HIGH, awaiting bubble-up of empty location.
- DIR(A) goes HIGH; (bubble-up delay after SO(A) LOW) an empty location is present at input stage of FIFO(A).

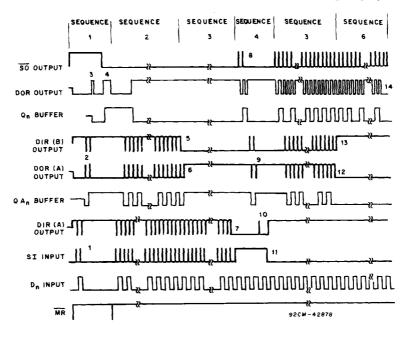


Fig. 19 - Function and intercommunication timing waveforms between two cascaded FIFOs (see Fig. 16 for corresponding pin description).

#### NOTES:

#### Sequence 1:

### Both FIFOs are empty shift-in process starts.

After a  $\overline{MR}$  pulse has been applied FIFO A and FIFO B are both empty. The DOR flag of both FIFOs become LOW because no valid data is present at the outputs. The DIR flags are set HIGH because the FIFOs are ready to accept data.  $\overline{SO}$ ; (B) is held HIGH and two SI(A) pulses are applied (see instant 1). These pulses allow two data words to ripple through to the output stage of FIFO A, and they are loaded into FIFO B (see instant 2). When data arrives at the output of FIFO B, a DOR(B) pulse is generated (see instant 3). When at instant 4,  $\overline{SO}$  (B) is turned LOW the first bit is shifted out and the second bit ripples to the output after which DOR(B) becomes HIGH.

# Sequence 2:

#### FIFO B runs full.

After a  $\overline{\text{MR}}$  pulse, a series of 64 SI pulses are applied by which 64 words are shifted in. Finally DIR(B) remains LOW because FIFO B is full (see instant 5). DOR(A) ends up LOW because FIFO A is again empty.

# Sequence 3:

### FIFO A runs full.

When 65 words are shifted in, DOR(A) remains HIGH because valid data remains at the output stage of FIFO A. After this Q<sub>n</sub>(A) remains HIGH being the polarity of the applied 65th data word (see instant 6). After the 128th SI pulse DIR(A) remains LOW because both FIFOs are full (see instant 7). At additional SI pulses no data transfer occurs.

### Sequence 4:

### Both FIFOs are full shift out process starts.

SI(A) held HIGH and two  $\overline{SO}$  (B) pulses are applied (see instant 8). These pulses shift out two words and thus allow two empty locations to bubble up to the input stage of FIFO B, and then proceeding their way to FIFO A (see instant 9). When the first empty location arrives at the input of FIFO A a new word is shifted in immediately during which a DIR(A) pulse is generated (see instant 10). When at instant 11, SI is turned down the second empty location reaches the input after which DIR(A) remains HIGH.

#### Sequence 5:

### FIFO A runs empty.

FIFO A contains 63 valid words now, because in sequence 4 two words were shifted out and one was shifted in again. An additional series of  $\overline{SO}$ , (B) pulses is applied. After 63  $\overline{SO}$ , (B) pulses all words from FIFO A are shifted into FIFO B, DOR(A) remains LOW (see instant 12).

## Sequence 6:

# FIFO B runs empty.

After the next \$\overline{SO}\$ (B) pulse, DIR(B) remains HIGH, because the input stage of FIFO B is empty now (see instant 13). After another 63 \$\overline{SO}\$ (B) pulses, DOR(B) remains LOW, because both FIFOs are empty again (see instant 14). Additional \$\overline{SO}\$ (B) pulses don't result in a transfer of information, but the last word remains available at the output Q<sub>n</sub>.